#### **PN Junction**

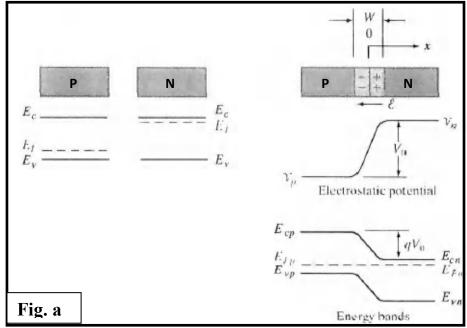
Most semiconductor devices contain at least one junction between p-type and n-type material. These p-n junctions are fundamental to the performance of functions such as rectification, amplification, switching, and other operations in electronic circuits.

### **Contact Potential:**

Let us consider separate regions of p- and n-type semiconductor material, brought together to form a junction (this is not a practical way of forming a device, but this "thought experiment" is to discover the requirements of equilibrium at a junction). Before they are joined, the n material has a large concentration of electrons and few holes, whereas the converse is true for the p material.

Upon joining the two regions, we expect diffusion of carriers to take place because of the large carrier concentration gradients at the junction. Thus holes diffuse from the p side into the n side, and electrons diffuse from n to p. The resulting diffusion current cannot build up indefinitely, however, because an opposing electric field is created at the junction.

If we consider that electrons are diffusing from n to p leave behind uncompensated donor ions  $(N_d^+)$  in the n material, and holes leaving the p region leave behind uncompensated acceptors  $(N_a^-)$ , it is easy to visualize the development of a region of positive space charge towards the n side of the junction and negative charge towards the p side. The resulting electric field is directed from the positive charge toward the negative charge.



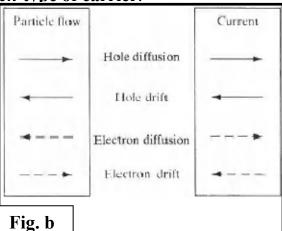
Thus electric field E is in the direction opposite to that of diffusion current for each type of carrier. Therefore, the field creates a drift component of current from n to p, opposing the diffusion current.

Since we know that no *net* current can flow across the junction at equilibrium (i.e., no external voltage applied), the current due to the drift of carriers in the E field must exactly cancel the diffusion current. Furthermore, since there can be no net buildup of electrons or holes on either side as a function of time, the drift and diffusion currents must cancel for *each* type of carrier.

 $J_p(drift)+J_p(diffusion)=0$  $J_n(drift)+J_n(diffusion)=0$ 

Therefore, the electric field E is built up to the point where the net current is zero at equilibrium. The electric field appears in some region W about the junction, and there is an equilibrium potential difference  $V_0$  across W.

There is a gradient in potential (Fig.a) in the direction opposite to electric field E where, E=-dV/dx.



Consider, the electric field is zero in the neutral regions outside W. Therefore, a constant potential  $V_n$  in the neutral n material, a constant  $V_p$  in the neutral p material exist, and a potential difference  $V_0 = V_n - V_p$  (as positive in n side) is developed between the two.

The region W is called the transition region (also called depletion region or space charge region or junction region), and the potential difference  $V_0$  is called the contact potential.

The contact potential appearing across W is a built-in potential barrier, necessary to maintain equilibrium at the junction; it does not imply any external potential.

The contact potential cannot be measured by placing a voltmeter across the devices, because new contact potentials are formed at each probe, just canceling  $V_0$ . By definition  $V_a$  is an equilibrium quantity, and no net current can be produced from it.

The contact potential separates the valence and conduction energy bands by the amount  $qV_0$  (Fig. a). The separation of the bands at equilibrium is just that required to make the Fermi level constant throughout the device.

#### Relationship between $V_0$ and the doping concentrations:

At equilibrium, the drift and diffusion components of the hole current just cancel out each other.

$$J_{p}(x) = q \left[ \mu_{p} p(x) E(x) - D_{p} \frac{dp(x)}{dx} \right] = 0$$

Rearranging the equation it can be obtained that

$$\frac{\mu_{p}}{D_{p}}E(x) - \frac{1}{p(x)}\frac{dp(x)}{dx} = 0 \Rightarrow \frac{\mu_{p}}{D_{p}}E(x) = \frac{1}{p(x)}\frac{dp(x)}{dx}$$

Now, using 
$$E(x) = -\frac{dV}{dx}$$
 &  $\frac{D_p}{\mu_p} = \frac{kT}{q}$  (Einstein equation)

$$-\frac{\mathbf{q}}{\mathbf{k}T}\frac{\mathbf{dV}}{\mathbf{dx}} = \frac{1}{\mathbf{p}(\mathbf{x})}\frac{\mathbf{dp}(\mathbf{x})}{\mathbf{dx}}$$

In case of PN junction, we are interested in the potential on either side of the junction,  $V_p$  and  $V_n$ , and the hole concentration just at the edge of the transition region on either side,  $p_p$  and  $p_n$ .

$$-\frac{q}{kT}\int_{V_p}^{V_n} dV = \int_{p_p}^{p_n} \frac{1}{p} dp$$

$$\Rightarrow -\frac{q}{kT} \left( V_n - V_p \right) = -\frac{q}{kT} V_0 = \ln(p_n) - \ln(p_p) = \ln(p_n/p_p)$$

$$\Rightarrow V_{_{0}} = \frac{kT}{q} ln \frac{p_{_{p}}}{p_{_{n}}}$$

If we consider the step junction to be made up of material with  $N_a$  acceptors/cm<sup>3</sup> on the p side and a concentration of  $N_d$  donors/cm<sup>3</sup> on the n side, we can write the above equation as

$$V_0 = \frac{kT}{q} \ln \frac{p_p}{p_n} = \frac{kT}{q} \ln \frac{N_a}{n_i^2 / N_d} = \frac{kT}{q} \ln \frac{N_d N_a}{n_i^2}$$

Also, the above relationship can be written as

$$\Rightarrow \frac{\mathbf{p}_{\mathbf{p}}}{\mathbf{p}_{\mathbf{n}}} = \mathbf{e}^{qV_0/kT}$$

Using the equilibrium condition,  $p_p n_p = n_i^2 = p_n n_n$ , we can write

$$\frac{p_{_p}}{p_{_n}} = \frac{n_{_n}}{n_{_p}} = e^{qV_0/kT}$$

## **Space charge at a junction**

Within the transition region, electrons and holes are in transit from one side of the junction to the other. Some electrons diffuse from n to p, and some are swept by the electric field from p to n (and conversely for holes). To a good approximation, we can consider the space charge within the transition region is due to the uncompensated donor and acceptor ions only. The charge density within W is plotted in following Fig.

Neglecting carriers within the space charge region, the charge density on the n side is just q times the concentration of donor ions  $N_d$ , and the negative charge density on the p side is -q times the concentration of acceptors Na. The assumption of carrier depletion within W and neutrality outside W is known as the *depletion approximation*.

Since the dipole about the junction must have an equal number of charges on either side, the transition region may extend into the p and n regions unequally, if doping concentrations are different in P and N side. For example, if the p side is more lightly doped than the n side  $(N_a < N_d)$ , the space charge region must extend farther

into the p material than into the n,

$$qAx_{p0}N_{a} = qAx_{n0}N_{p}$$

Total width of the transition region

$$W=X_{n\theta}+X_{p\theta}$$

According to the Poisson's equation

$$\vec{\nabla}.\vec{E} = \frac{\rho}{\epsilon}, \implies \frac{dE}{dx} = \frac{q}{\epsilon} \left( p - n + N_d^+ - N_a^- \right)$$

For depletion region, p-n=0

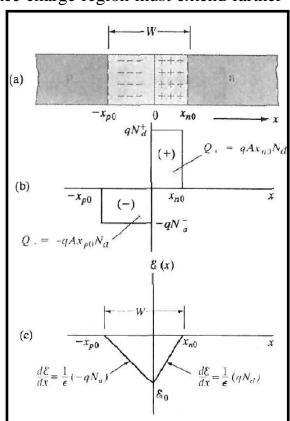
$$\Rightarrow \frac{dE}{dx} = \frac{q}{\epsilon} N_d \text{ for } 0 < x < x_{n0};$$

$$\Rightarrow \frac{dE}{dx} = -\frac{q}{\epsilon} N_a \text{ for } -x_{p_0} < x < 0$$

(For complete ionization:  $N_d^+=N_d$ ,  $N_a^-=N_a$ )

$$\int\limits_{E_0}^0 dE = \frac{q}{\epsilon} N_{_d} \int\limits_{_0}^{x_{_{n_0}}} dx, \quad for \ 0 < x < x_{_{n_0}}$$

$$\int_{0}^{E_{0}} dE = -\frac{q}{\epsilon} N_{d} \int_{-x}^{0} dx, \text{ for } -x_{p0} < x < 0$$



Therefore, the maximum value of the electric field is

$$\mathbf{E}_{0} = -\frac{\mathbf{q}}{\varepsilon} \mathbf{N}_{d} \mathbf{x}_{no} = -\frac{\mathbf{q}}{\varepsilon} \mathbf{N}_{a} \mathbf{x}_{p0}$$

It is simple to relate the electric field to the contact potential  $V_0$ , since the E field at any x is the negative of the potential gradient at that point:

$$E(x) = -\frac{dV}{dX} \implies -V_0 = \int_{-x_{n,0}}^{x_{n,0}} E(x) dx$$

Thus the negative of the contact potential is simply the area under the E(x) vs. x triangle.

$$V_{0} = -\frac{1}{2} E_{0} (x_{n0} + x_{p0}) = -\frac{1}{2} E_{0} W = \frac{1}{2} \frac{q}{\epsilon} N_{d} x_{n0} W$$

Now, 
$$X_{n0}N_d = X_{p0}N_a$$
, and  $W = X_{n0} + X_{p0}$ 

Then, 
$$X_{n0}N_d = X_{p0}N_a = (W - X_{n0})N_a \Rightarrow X_{n0} = \frac{WN_a}{N_a + N_d}$$

$$\therefore V_0 = \frac{1}{2} \frac{q}{\epsilon} N_d X_{n0} W = \frac{1}{2} \frac{q}{\epsilon} N_d \frac{W N_a}{N_a + N_d} \cdot W = \frac{1}{2} \frac{q}{\epsilon} \frac{N_d N_a}{N_a + N_d} \cdot W^2$$

$$\therefore \mathbf{W} = \left[\frac{2\epsilon V_0}{q} \left(\frac{\mathbf{N_d} + \mathbf{N_a}}{\mathbf{N_d} \mathbf{N_a}}\right)\right]^{\frac{1}{2}} = \left[\frac{2\epsilon V_0}{q} \left(\frac{1}{\mathbf{N_d}} + \frac{1}{\mathbf{N_a}}\right)\right]^{\frac{1}{2}}$$

$$\therefore X_{p0} = \frac{WN_{d}}{N_{a} + N_{d}} = \frac{N_{d}}{N_{a} + N_{d}} \left[ \frac{2\epsilon V_{0}}{q} \left( \frac{N_{d} + N_{a}}{N_{d}N_{a}} \right) \right]^{\frac{1}{2}} = \left[ \frac{2\epsilon V_{0}}{q} \left( \frac{N_{d}}{N_{a}(N_{d} + N_{a})} \right) \right]^{\frac{1}{2}}$$

$$\therefore X_{n0} = \frac{WN_{a}}{N_{a} + N_{d}} = \frac{N_{a}}{N_{a} + N_{d}} \left[ \frac{2\epsilon V_{0}}{q} \left( \frac{N_{d} + N_{a}}{N_{d}N_{a}} \right) \right]^{\frac{1}{2}} = \left[ \frac{2\epsilon V_{0}}{q} \left( \frac{N_{a}}{N_{d}(N_{d} + N_{a})} \right) \right]^{\frac{1}{2}}$$

An abrupt Si p-n junction has  $Na = 10^{18} \text{cm}^{-3}$  on one side and  $Nd = 5x \ 1015 \text{cm}^{-3}$  on the other.

- (a) Calculate the Fermi level positions at 300 K in the p and n regions.
- (b) Draw an equilibrium band diagram for the junction and determine the contacpotential  $V_0$  from the diagram.
- (c) Consider the semiconductor piece has a circular cross section with a diameter of 10  $\mu$ m. Calculate  $x_{n0}$ ,  $x_{p0}$ , Q+,  $E_0$  (300 K).
- (d) Sketch E(x) and charge density to the scale.

<u>(a)</u>

$$E_{ip} - E_F = kT \ln \frac{p_p}{n_i} = 0.0259 \ln \frac{10^{18}}{(1.5 \times 10^{10})} = 0.467 \text{ eV}$$

$$E_F - E_{in} = kT \ln \frac{n_n}{n_i} = 0.0259 \ln \frac{5 \times 10^{15}}{(1.5 \times 10^{10})} = 0.329 \text{ eV}$$

$$qV_0 = 0.467 + 0.329 = 0.796 \text{ eV}$$

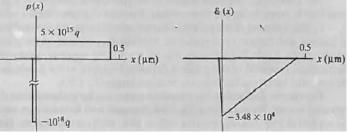
<u>(b)</u>

$$E_{ip}$$
 0.796 eV  $E_{en}$   $E_{vp}$  0.329 eV  $E_{in}$   $E_{vn}$ 

(c) 
$$A = \pi (5 \times 10^{-4})^2 = 7.85 \times 10^{-7} \text{cm}^2$$
  
 $W = \left[\frac{2 \epsilon V_0}{q} \left(\frac{1}{N_a} + \frac{1}{N_d}\right)\right]^{1/2}$   
 $= \left[\frac{2(11.8)(8.85 \times 10^{-14})(0.796)}{1.6 \times 10^{-19}} (10^{-18} + 2 \times 10^{-16})\right]^{1/2} = 0.457 \, \mu\text{m}$   
 $x_{n_0} = \frac{W}{1 + N_d/N_a} = \frac{0.457}{1 + 5 \times 10^{-3}} = 0.455 \, \mu\text{m} \, x_{p_0} = \frac{0.457}{1 + 200} = 2.27 \times 10^{-3} \, \mu\text{m}$   
 $Q_+ = qAx_{n_0}N_d = qAx_{p_0}N_a = (1.6 \times 10^{-19})(7.85 \times 10^{-7})(2.27 \times 10^{11})$   
 $= 2.85 \times 10^{-14}\text{C}$   
 $\mathcal{E}_0 = -\frac{q}{\epsilon}x_{n_0}N_d = -\frac{q}{\epsilon}x_{p_0}N_a = \frac{1.6 \times 10^{-19}}{(11.8)(8.85 \times 10^{-14})}(2.27 \times 10^{11})$   
 $= -3.48 \times 10^4 \, \text{V/cm}$ 

Note:

 $qV_0 = \Delta E_{Fn} + \Delta E_{Fp} = E_{vp} - E_{vn} = E_{Cp} - E_{Cn}$ 



# $\underline{\text{Prove: } \mathbf{q}\mathbf{V}_{\underline{0}}} = \underline{\mathbf{E}}_{\mathbf{V}\underline{\mathbf{p}}} - \underline{\mathbf{E}}_{\mathbf{V}\underline{\mathbf{n}}}$

$$\frac{p_p}{p_n} = e^{qV_0/kT} = \frac{N_v e^{-(E_{F\rho} - E_{vp})/kT}}{N_v e^{-(E_{F\alpha} - E_{vn})/kT}}$$

$$e^{qV_0/kT} = e^{(E_{F\alpha} - E_{F\rho})/kT} e^{(E_{v\rho} - E_{vn})/kT}$$

$$qV_0 = E_{v\rho} - E_{vn}$$

Prove:  $qV_0 = \Delta E_{Fp} + \Delta E_{Fn}$ 

$$e^{qV_0/kT} = \frac{p_p}{p_n} = \frac{p_p}{n_i^2/n_n} = \frac{p_p.n_n}{n_i^2} = \frac{p_p.n_n}{n_ip_i} = \frac{N_v e^{-(E_{Fp}-E_v)/kT}.N_c e^{-(E_c-E_{Fn})/kT}}{N_v e^{-(E_i-E_v)/kT}.N_c e^{-(E_c-E_i)/kT}}$$

$$e^{qV_0/kT} = exp[(-E_{Fp} + E_{V} - E_{C} + E_{Fn} + E_{i} - E_{V} + E_{C} - E_{i})/kT]$$

$$= exp[((E_{i} - E_{Fp}) + (E_{Fn} - E_{i}))/kT] = exp[(\Delta E_{Fp} + \Delta E_{Fn})/kT]$$

Hence,  $qV_0 = \Delta E_{Fp} + \Delta E_{Fn}$